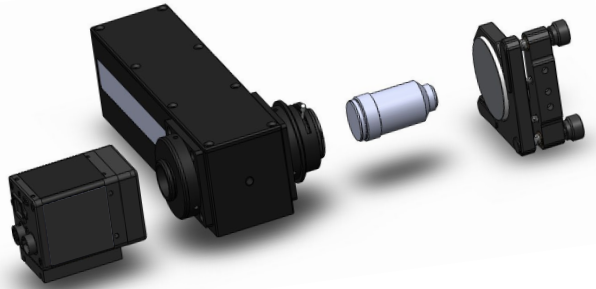# Kaleo Kit
## Fully modular metrology solution from UV to IR
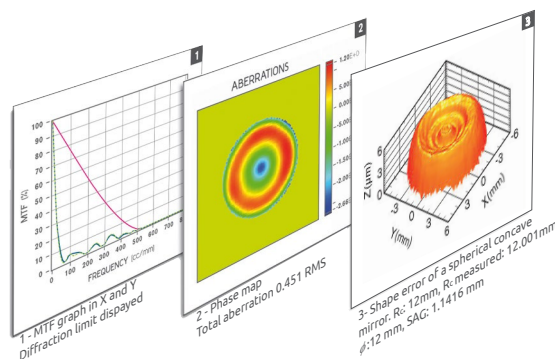
**PHASICS**
the phase control company

# ASSEMBLE YOUR OWN MODULAR METROLOGY SYSTEM...

With the rise in complexity of optical systems, metrology teams often need **specific measurement parameters** (test wavelength, accuracy, resolution, relevant outcomes...). PHASICS answers this challenge with **Kaleo Kit**, its modular system for optics qualification.

**Kaleo Kit** is the combination of a broad range of compatible modules, that let you create a **cost-effective, compact, and easy-to-use system** that can adapt to a wide range of measurement configurations and ensure the quality of your sample at all development stages.

Access all the characteristics of your sample in a **single shot acquisition**: TWE, RWE, wavefront aberrations, MTF, PSF, and a lot more!



1 - MTF graph in X and Y
Diffraction limit dispayed

2 - Phase map
Total aberration 0.451 RMS

3 - Shape error of a spherical concave mirror, R: 12mm, R: measured: 12.001mm
⌀:12 mm, SAG: 1.1416 mm

**PHASICS -** the phase control company

# ... IN JUST 3 EASY STEPS

## 1 Choose YOUR Wavefront Sensor

| SID4 Model | Spectral Range (nm) | Sampling (px) |
|---|---|---|
| SID4-UV | 250-400 | 250x250 |
| SID4 | 400-1100 | 160x120 |
| SID4-HR | 400-1100 | 400x300 |
| SID4-SWIR | 900-1700 | 80x64 |
| SID4-SWIR-HR | 900-1700 | 160x128 |
| SID4-DWIR | 3000-5000 | 160x120 |

## 2 Select YOUR R-Cube

| Wavelength * (nm) | |
|---|---|
| 365 | 810 |
| 405 | 850 |
| 530 | 940 |
| 625 | 1050 |
| 740 | 1550 |
| 780 | 3900 |

## 3 Shape YOUR beam

| Beam Expander * Exit pupil diameter (mm) | | Focusing System * F# |
|---|---|---|
| 8 | | 0.6 |
| 15 | | 1 |
| 30 | OR | 1.6 |
| 60 | | 2.5 |
| 130 | | 5 |
| | | 10 |

+ Reference mirror (flat or sphere)

\* more options upon request

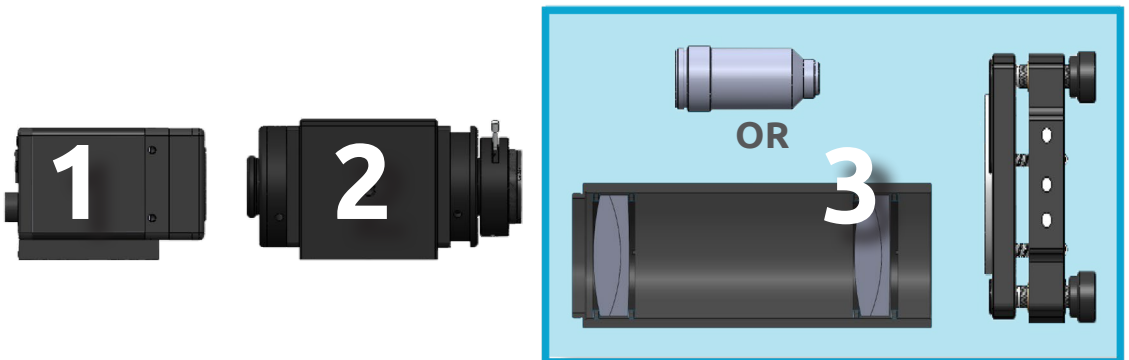# ACCORDING TO YOUR SPECIFIC REQUIREMENTS

## VERSATILE
- Available from UV to IR
- Modules compatible with stand-alone use
- All measurement configurations: finite-finite, infinite-finite...
- Same modules fit for different setups

## POWERFUL UNIQUE TECHNOLOGY
- High resolution
- Dedicated to large aberrations measurement
- Achromatic measurement: for any test wavelength
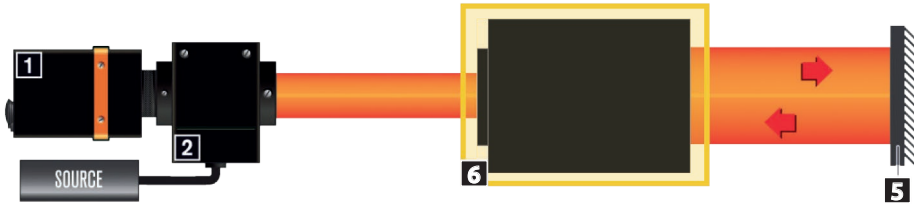- Nanometric sensitivity

## EASY-TO-USE
- Compact
- Designed for easy alignment
- Quick access to all results

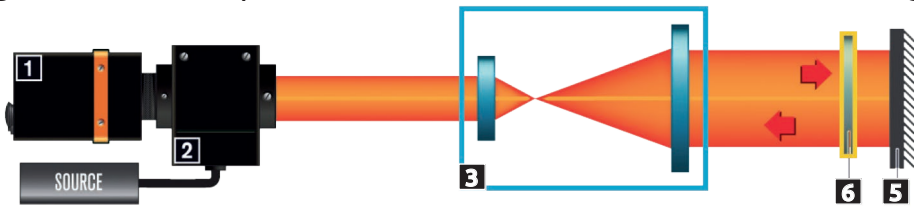# ADAPTED TO ALL APPLICATIONS

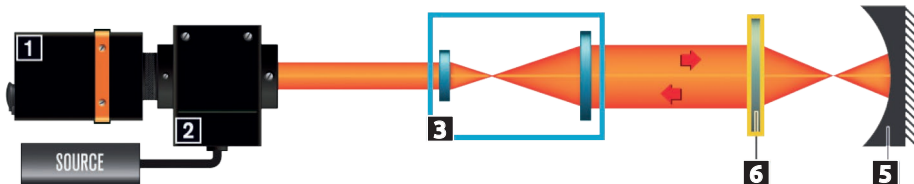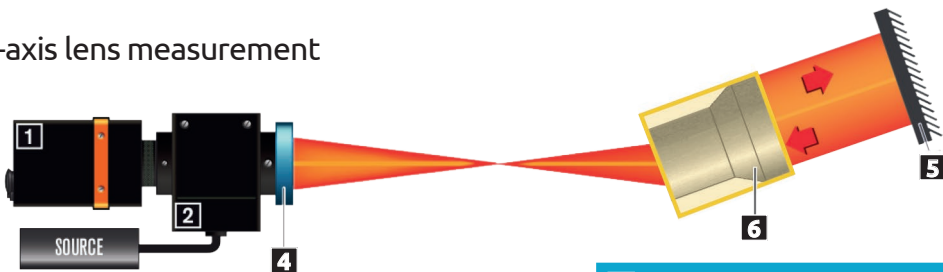- Telescope alignment and characterization

- Concave mirror measurement

- Large diameter flat optics characterization: Filters, Windows, Polarizing optics

- Large diameter lens & objective measurement in any configuration

- Off-axis lens measurement

**Kaleo Kit modules**

1 SID4 Wavefront sensor
2 R-Cube
3 Beam expander
4 Focusing system
5 Reference mirror
6 System under test